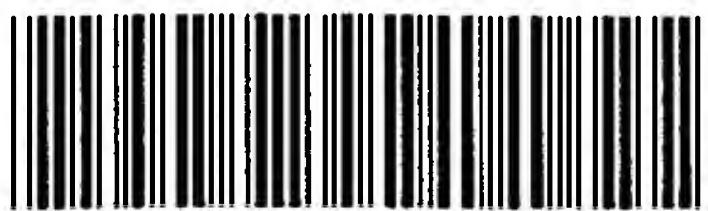


## **Search Notes**



**Application/Control No.**

10/710,667

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Examiner

Jason Uhlenhake

**Applicant(s)/Patent under  
Reexamination**

CHANG, WEN-CHI

## **Art Unit**

2853

**SEARCHED**

# **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>